Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/841,666	TANAKA ET AL.
Examiner	Art Unit
HOAN C. NGUYEN	2871

SEARCHED				
Class	Subclass	Date	Examiner	
349	112	7/16/2007	CHN	
362	333, 339	7/16/2007	CHN	
428	172	7/16/2007	CHN	
425	373-374	7/16/2007	CHN	
156	462	7/16/2007	CHN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	es above and search	7/16/2007	CHN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
East search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	7/16/2007	CHN	